In the Claims

Claims 1-7 (Cancelled)

8. (Previously Presented) A switch comprising:

a plurality of dual-gate field effect transistors connected in series, each dual-gate field effect transistor including two gates, a source, and a drain;

one of said series connected dual-gate field effect transistors having a modified gate therein, said modified gate having a length that is of a different size from gate lengths of other series connected dual-gate field effect transistors.

Claim 9 (Cancelled)

- 10. (Original) The switch as claimed in claim 8, wherein said modified gate of said series connected dual-gate field effect transistor has a distance to its drain port that is less than a distance to its source port.
- 11. (Original) The switch as claimed in claim 8, wherein said modified gate of said series connected dual-gate field effect transistor has a distance to its source port that is less than a distance to its drain port.
- 12. (Original) The switch as claimed in claim 10, wherein gates of said other series connected dual-gate field effect transistors have a distance to its source port that is equal to a distance to its drain port.
- 13. (Original) The switch as claimed in claim 11, wherein gates of said other series connected dual-gate field effect transistors have a distance to its source port that is equal to a distance to its drain port.

- 14. (Original) The switch as claimed in claim 8, wherein a second series connected dual-gate field effect transistor has a modified gate therein that is of a different size from gates of other series connected dual-gate field effect transistors.
- 15. (Original) The switch as claimed in claim 8, wherein said dual-gate field effect transistors are high-electron-mobility-transistors.
- 16. (Original) The switch as claimed in claim 8, wherein the different gate sizes increase a parasitic capacitance within the switch.
 - 17. (Previously Presented) A switch comprising:

a plurality of dual-gate field effect transistors connected in series, each dual-gate field effect transistor including two gates, a source, and a drain;

one of said series connected dual-gate field effect transistors having a modified gate therein that is of a different size from gates of other series connected dual-gate field effect transistors;

said dual-gate field effect transistors include a transistor connection segment between said gates and a heavily doped cap layer fabricated upon said transistor connection segment between said gates.

Claim 18 (Cancelled)

- 19. (Previously Presented) A high-electron-mobility-transistor, comprising: two gate fingers;
- a transistor connection segment between said gate fingers; and
- a heavily doped cap layer fabricated upon said transistor connection segment between said gate fingers;

said gate fingers being of different sizes.

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- 20. (Original) The high-electron-mobility-transistor as claimed in claim 19, wherein one of said gate fingers has a distance to its source port that is less than a distance to its drain port.
- 21. (Original) The high-electron-mobility-transistor as claimed in claim 19, wherein one of said gate fingers has a distance to its drain port that is less than a distance to its source port.
- 22. (Previously Presented) A radio frequency single pole double throw switch, comprising:
 - a receiver port;
 - a transmitter port;
 - an antenna port;
 - a receiver section connecting said receiver port to said antenna; and
 - a transmitter section connecting said transmitter port to said antenna;
- said receiver section including a plurality of dual-gate field effect transistors connected in series, each dual-gate field effect transistor including two gates, a source, and a drain such that one of said series connected dual-gate field effect transistors has a modified gate therein, said modified gate having a length that is of a different size from gate lengths of other series connected dual-gate field effect transistors.
- 23. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein a source of said modified gate transistor is connected to said receiver port.
- 24. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein a drain of said modified gate transistor is connected to said antenna port.

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- 25. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein a second series connected dual-gate field effect transistor has a second modified gate therein that is of a different size from gates of other series connected dual-gate field effect transistors.
- 26. (Original) The radio frequency single pole double throw switch as claimed in claim 25, wherein a source of said modified gate transistor is connected to said receiver port and a drain of said second modified gate transistor is connected to said antenna port.
- 27. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein said dual-gate field effect transistors are high-electron-mobility-transistors.
- 28. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein said modified gate of said series connected dual-gate field effect transistor has a longer gate length and/or gate width than gates of said other series connected dual-gate field effect transistor.
- 29. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein said modified gate of said series connected dual-gate field effect transistor has a distance to its drain port that is less than a distance to its source port.
- 30. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein said modified gate of said series connected dual-gate field effect transistor has a distance to its source port that is less than a distance to its drain port.
- 31. (Original) The radio frequency single pole double throw switch as claimed in claim 29, wherein gates of said other series connected dual-gate field effect transistors have a distance to its source port that is equal to a distance to its drain port.

- 32. (Original) The radio frequency single pole double throw switch as claimed in claim 30, wherein gates of said other series connected dual-gate field effect transistors have a distance to its source port that is equal to a distance to its drain port.
- 33. (Original) The radio frequency single pole double throw switch as claimed in claim 22, wherein the different gate sizes increase a parasitic capacitance within the switch.
- 34. (Previously Presented) A radio frequency single pole double throw switch comprising:

a receiver port;

a transmitter port;

an antenna port;

a receiver section connecting said receiver port to said antenna; and

a transmitter section connecting said transmitter port to said antenna;

said receiver section including a plurality of dual-gate field effect transistors connected in series, each dual-gate field effect transistor including two gates, a source, and a drain such that one of said series connected dual-gate field effect transistors has a modified gate therein that is of a different size from gates of other series connected dual-gate field effect transistors;

said dual-gate field effect transistors include a transistor connection segment between said gates and a heavily doped cap layer fabricated upon said transistor connection segment between said gates.

Claims 35-37 (Cancelled)

- 38. (Previously Presented) The radio frequency single pole double throw switch as claimed in claim 39, wherein said transmitter section includes a first transmitter dualgate high electron mobility transistor having gates of different lengths and a second transmitter dual-gate high electron mobility transistor having gates of different lengths.
- 39. (Previously Presented) A radio frequency single pole double throw switch comprising:
 - a receiver port;
 - a transmitter port;
 - an antenna port;
 - a receiver section connecting said receiver port to said antenna; and a transmitter section connecting said transmitter port to said antenna; said receiver section including,
 - a first receiver dual-gate high electron mobility transistor having gates of different lengths, and
 - a second receiver dual-gate high electron mobility transistor having gates of different lengths;

said transmitter section including a first transmitter dual-gate high electron mobility transistor having gates of different lengths and a second transmitter dual-gate high electron mobility transistor having gates of different lengths;

said first transmitter dual-gate high electron mobility transistor having a source, said source being connected to said receiver port and the drain of said second transmitter dual-gate high electron mobility transistor is connected to said antenna port.

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40. (Previously Presented) The radio frequency single pole double throw switch

as claimed in claim 39, wherein a first gate of said first receiver dual-gate high electron

mobility transistor has a longer gate length and/or gate width than a second gate of said

first receiver dual-gate high electron mobility transistor.

41. (Previously Presented) The radio frequency single pole double throw switch

as claimed in claim 39, wherein a first gate of said first receiver dual-gate high electron

mobility transistor has a distance to its drain port that is less than a distance to its

source port.

42. (Previously Presented) The radio frequency single pole double throw switch

as claimed in claim 39, wherein a first gate of said second receiver dual-gate high

electron mobility transistor has a distance to its source port that is less than a distance

to its drain port.

Cancelled Claims 43-44

45. (Previously Presented) The radio frequency single pole double throw switch

as claimed in claim 39, wherein the different gate lengths increase a parasitic

capacitance within the switch.

46. (Previously Presented) The radio frequency single pole double throw switch

claimed in claim 39, wherein the different gate lengths improve the linearity without

impacting the ESD and EOS ruggedness.

Claims 47-50 (Cancelled)

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